A.4 Best Practice Procedure for EOS Analysis in the Automotive Industry – How Can We Improve Our Knowledge Sharing?

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Failures for EOS represent a significant percentage of components returned by the OEM's to tier1 and semiconductor manufacturers for comprehensive failure analysis in the automotive industry. There is generally a requirement from the OEM to conduct a detailed investigation to determine the root cause of the failure; however, commonly this cannot be done due to missing information and poor communications. This workshop presents a new guideline that defines a procedure for information sharing between the OEM, tier1 and semiconductor manufacturers that can lead to a higher chance to identify the root cause of the damage. In this workshop, we would like to pose several questions: How can we learn from these findings? What are possible blocking points to this process? What would be the best feasible way to spread the information gathered during the investigations?